

MicroFinish Topographer (MFT)

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Product Demonstration

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Rochester, NY



Overview

Background/motivation

Root of roughness measurement problem

Solution to the problem; the MFT

Advantages of the MFT

MFT hardware solution

Results/data

Conclusion



Background/motivation

Measuring surface roughness on large optics

Currently done with replicas, but

Replicas require skill and time to make

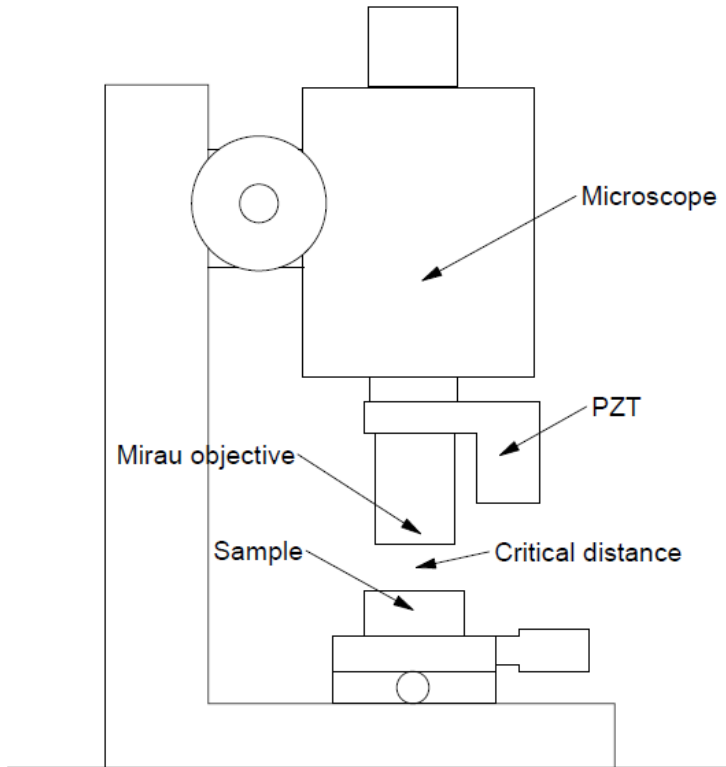
Question of fidelity of replication

Residue is detrimental and difficult to remove

Provoked thought about roughness measurement and instrument design for making measurements



Root of the problem



Design based on a classical microscope

Critical distance about 10 mm

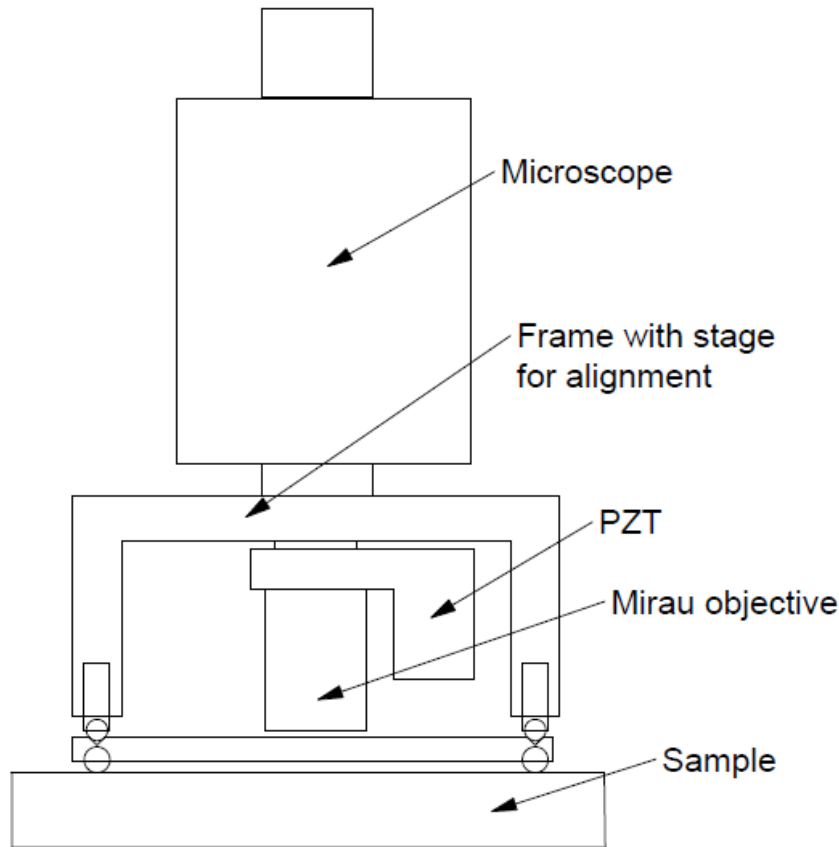
Need to maintain to nm level

“C” shaped mechanical path

about 400 mm including 3 stages

Sample referenced off rear

Basic MFT design



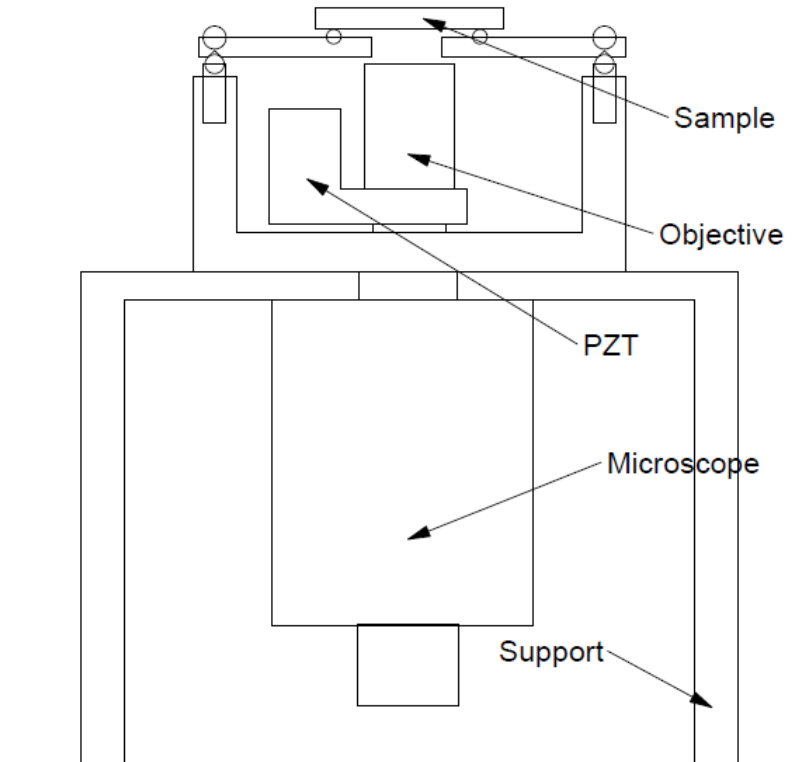
Short coupling between sample and objective

Stages built into frame

Microscope referenced to front of sample

Microscopes moves with front of sample

MFT for small samples



Keep short coupling for small samples by inverting

Microscope references front surface

Similar samples require no adjustment between them

Sample moves with microscope

Advantages of the MFT

Same instrument works for all sizes of samples

Quick change between configurations

MFT is largely insensitive to vibration

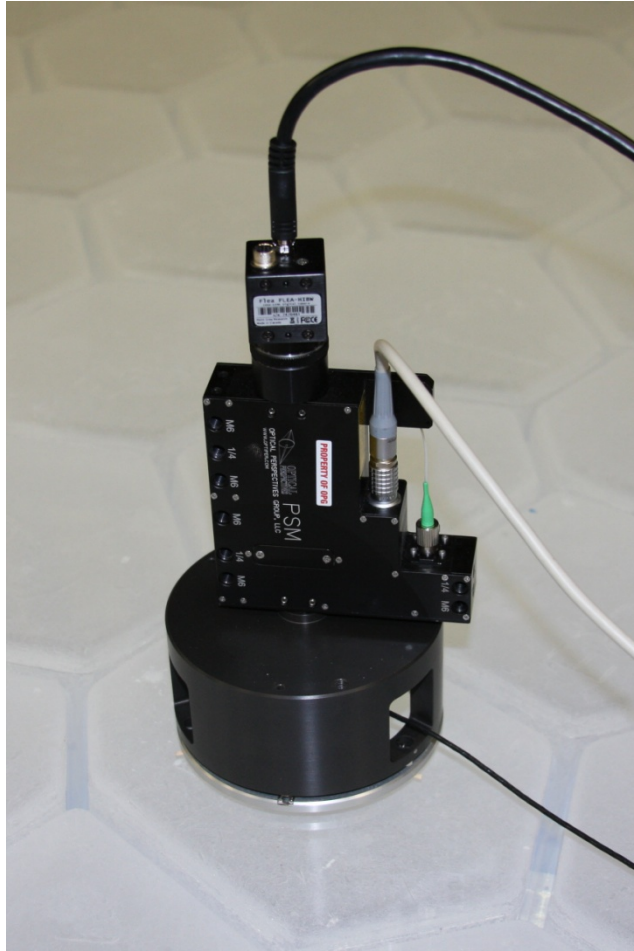
MFT is portable, can do on-machine metrology

Front surface reference means minimum of adjustment

Allows for rapid sample change and measurement



Hardware – MicroFinish Topographer



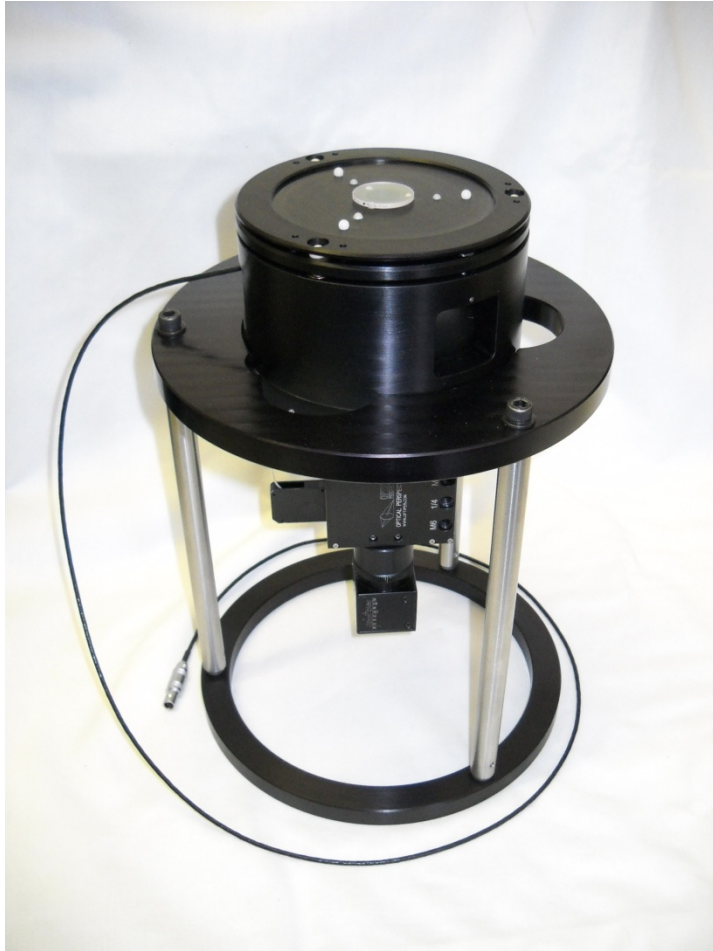
MFT on a large mirror

Uses the Point Source
Microscope as the microscope

Uses 4D 4Sight software for
phase stepping or ramping
data reduction

3 nylon balls sit directly on
mirror surface

MicroFinish Topographer - Inverted



25 mm sample for measurement

Three adjustments align for
tip/tilt and focus

Front surface reference means
rapid sample measurement

Little or no adjustment needed
sample to sample

Pat. Pending on design



Results of measurement

Use 4D 4Sight software

Aver. of 10 measurements

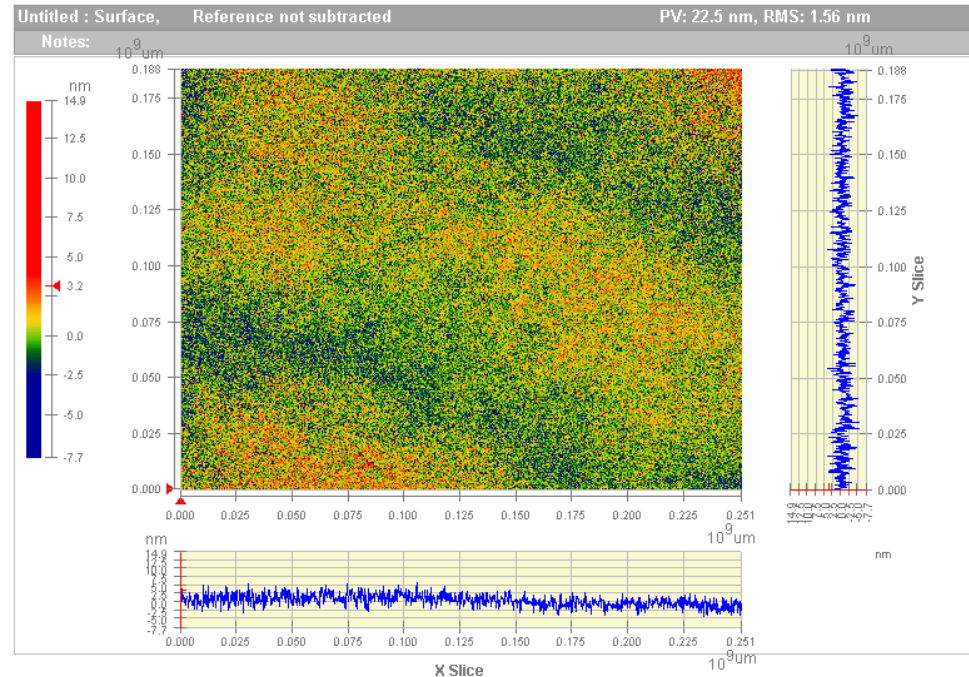
Pitch polished plano

Inverted configuration

No vibration isolation

No filtering

PV = 22.5 nm, rms = 1.56 nm



Good repeatability

	Meas.	Pv	rms	Valid pts	diff Pv	diff rms
10 single measurements						
Same sample	1	63.20	4.78	all	56.70	4.51
Same conditions	2	51.40	4.70	all	49.80	4.44
Pv and rms in nm	3	63.10	4.66	all	51.00	4.38
Valid data every point	4	58.50	4.58	all	53.20	4.31
Right, Average –	5	57.40	4.64	all	58.10	4.36
individual	6	51.50	4.68	all	51.50	4.39
	7	50.70	4.68	all	47.60	4.32
	8	50.00	4.63	all	50.40	4.35
	9	61.70	4.63	all	51.60	4.34
	10	55.30	4.52	all	56.90	4.28
	Average	22.9	1.57	average	52.68	4.368
St. Dev. PV = 3.5 nm				St. dev.	3.469	0.067
St. Dev. Rms = .067 nm						

PV & rms from sets of 10 meas. 22.41 and 1.59 nm



Good data consistency

Average of 10 single meas.

PV = 22.9, rms = 1.57

Expect noise reduction

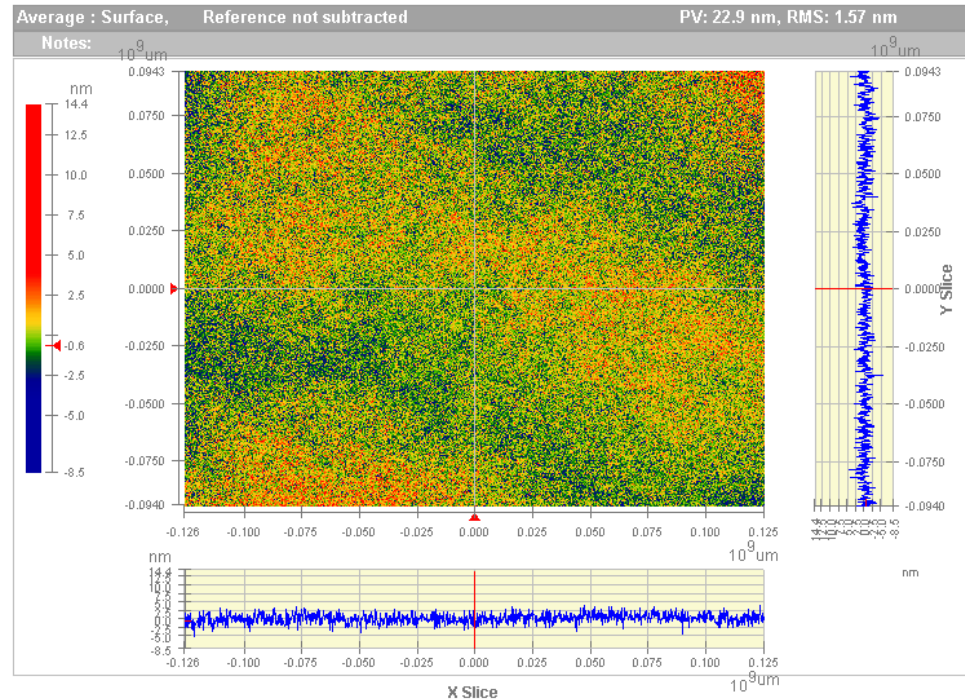
$\text{Sqrt}(10 - 1) = 3$

Aver. indiv PV = 56.28

$56.28/3 = 18.8$

Aver. Indiv. rms = 4.65

$4.65/3 = 1.55$



Height Calibration

Measure surface of known radius, for example, $R = 291 \text{ mm}$

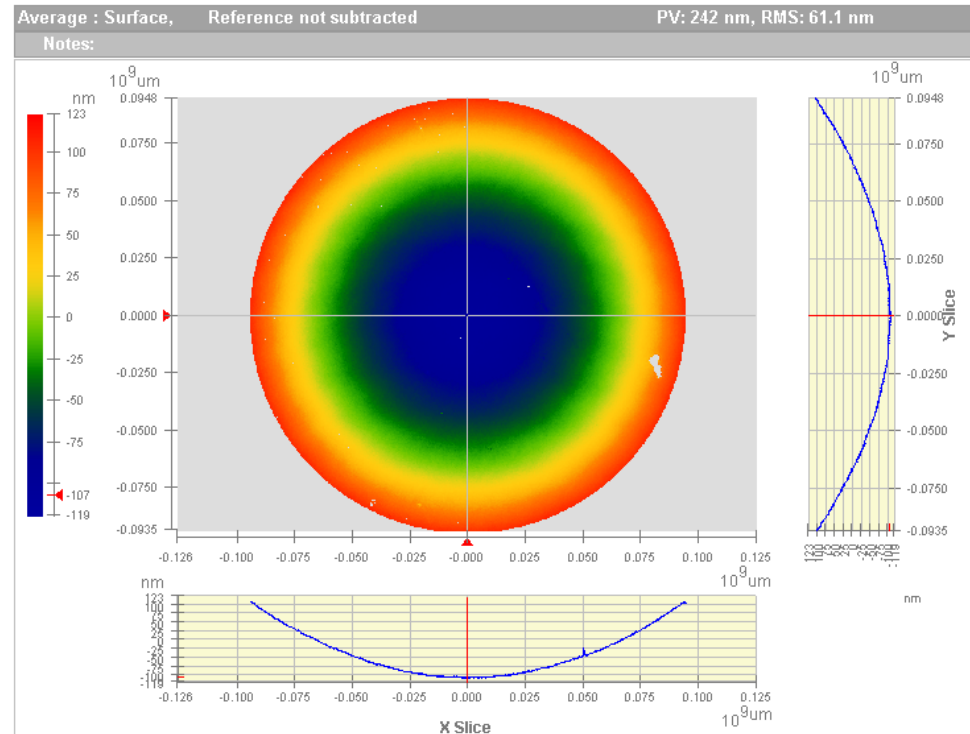
Calculate sag over width of sample viewed, $y = 711 \mu\text{m}$

$\text{Sag} = y^2 / 8 * R = 217 \text{ nm}$

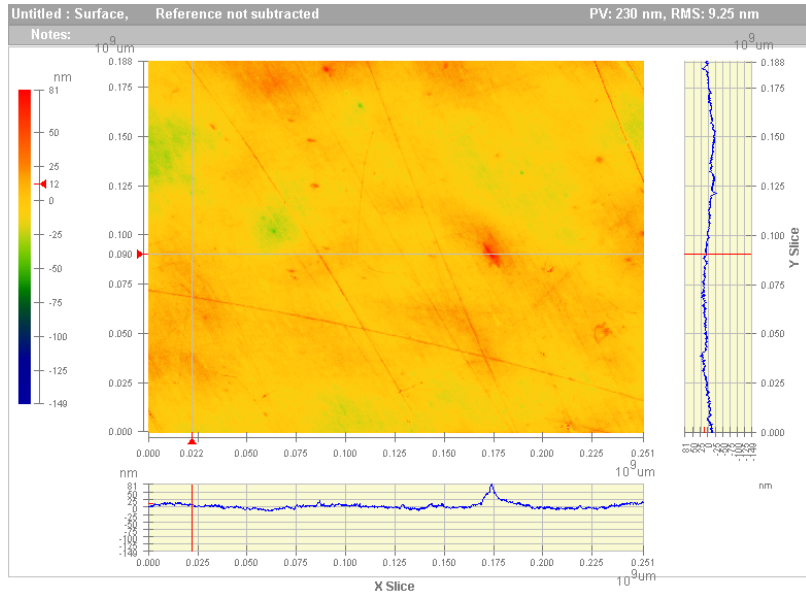
Average of 10 yields 212.5 nm

Std dev. of sag = 0.08 nm

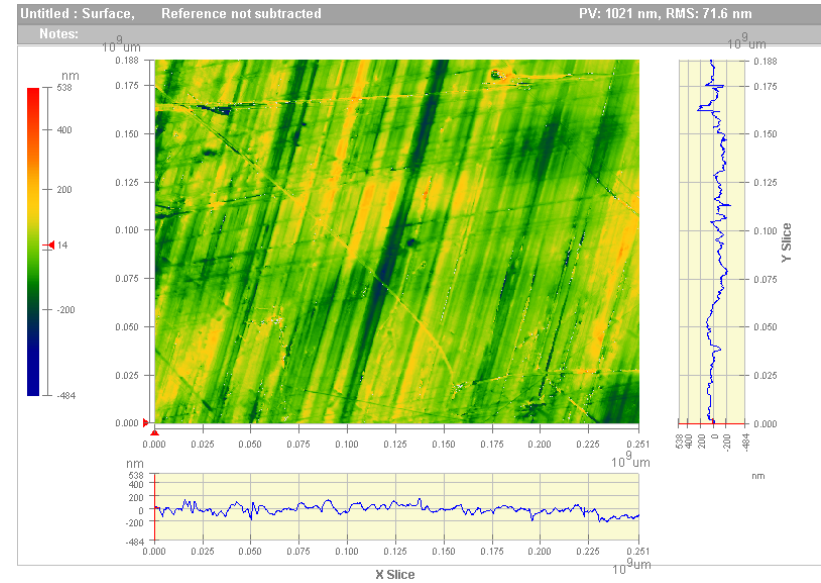
Based on 99% of all points



Other surfaces measured



Molded plastic
230 nm P-V, 9.25 nm rms



Machined aluminum
1021 nm P-V, 71.6 nm rms

Wrap-up

- Designed a micro roughness tester for any size sample
- Repeatable without vibration isolation
- Uses well vetted software
- Rapidly tests multiple samples of same geometry
- Designed for easy portability including a laptop
- Can be adapted to cylindrical surfaces with new interface

Come see us

For further info stop by at Booth 205

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